

AOD66920

100V N-Channel AlphaSGT[™]

General Description

- Trench Power AlphaSGT[™] technology
- Low $R_{DS(ON)}$
- Logic Level Driving
- Excellent Q_G x R_{DS(ON)} Product (FOM)
- RoHS and Halogen-Free Compliant

Applications

• High Frequency Switching and Synchronous Rectification

Product Summary

 $\begin{array}{lll} V_{DS} & 100V \\ I_{D} \; (at \, V_{GS} \! = \! 10V) & 70A \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 10V) & < 8.2 m\Omega \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 4.5V) & < 10.7 m\Omega \end{array}$

100% UIS Tested 100% Rg Tested

Form

35.5

6.2

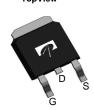
4.0

-55 to 150



TO252

TopView DPAK



 $T_{C}=100^{\circ}C$

T_A=25°C

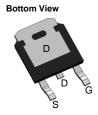
T_A=70°C

Junction and Storage Temperature Range

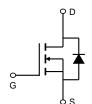
Power Dissipation B

Power Dissipation ^A

Orderable Part Number



Package Type



Minimum Order Quantity

W

W

°C

		3 71	_		
AOD66920		TO-252	Tape & Reel	2500	
Absolute Maximum	n Ratings T _A =25°C	unless otherwise not	red		
Parameter		Symbol Maximum		Units	
Drain-Source Voltage		V_{DS}	100	V	
Gate-Source Voltag	е	V_{GS}	±20	V	
Continuous Drain Current ^G	T _C =25°C		70		
	T _C =100°C	I _D	46.5	A	
Pulsed Drain Current ^C		I _{DM}	180		
Continuous Drain Current	T _A =25°C		19.5	A	
	T _A =70°C	IDSM	15.5		
Avalanche Current ^C		I _{AS}	38	A	
Avalanche energy	L=0.1mH ^C	E _{AS}	72	mJ	
	T _C =25°C	Б	89	20/	

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\theta,JA}$	15	20	°C/W			
Maximum Junction-to-Ambient AD	Steady-State	Т⊕ЈА	40	50	°C/W			
Maximum Junction-to-Case Steady-Stat		$R_{\theta JC}$	1.15	1.4	°C/W			

 P_{DSM}

 T_J , T_{STG}



Electrical Characteristics (T_{.I}=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units		
STATIC PARAMETERS									
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V		100			V		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =100V, V _{GS} =0V				1	μA		
	Zero Gate Voltage Drain Current		T _J =55°C			5	μΛ		
I_{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V				±100	nA		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$		1.5	2.0	2.5	V		
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =20A			6.7	8.2	mΩ		
			T _J =125°C		11.6	14	11122		
		V_{GS} =4.5V, I_{D} =20A			8.5	10.7	mΩ		
g _{FS}	Forward Transconductance	V_{DS} =5V, I_D =20A			65		S		
V_{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V			0.7	1	V		
Is	Maximum Body-Diode Continuous Current					70	Α		
DYNAMIC	PARAMETERS								
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =50V, f=1MHz			2500		pF		
C _{oss}	Output Capacitance				485		pF		
C _{rss}	Reverse Transfer Capacitance				13		pF		
R_g	Gate resistance	f=1MHz		0.5	1.1	1.7	Ω		
SWITCHI	NG PARAMETERS								
Q _g (10V)	Total Gate Charge				35	50	nC		
Q _g (4.5V)	Total Gate Charge	Vaa=10\/ \/aa=50\/	V -10V V -50V L-20A		16.7	25	nC		
Q_{gs}	Gate Source Charge	V _{GS} =10V, V _{DS} =50V, I _D =20A			8		nC		
Q_{gd}	Gate Drain Charge				5		nC		
Q _{oss}	Output Charge	V _{GS} =0V, V _{DS} =50V			44		nC		
t _{D(on)}	Turn-On DelayTime				10		ns		
t _r	Turn-On Rise Time	V_{GS} =10V, V_{DS} =50V, R_L =2.5 Ω , R_{GEN} =3 Ω			4		ns		
t _{D(off)}	Turn-Off DelayTime				31		ns		
t _f	Turn-Off Fall Time				6		ns		
t _{rr}	Body Diode Reverse Recovery Time	I _F =20A, di/dt=500A/μs			34		ns		
Q_{rr}	Body Diode Reverse Recovery Charge	l _F =20A, di/dt=500A/μs			170		nC		

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on R_{0JA} t≤ 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

- C. Single pulse width limited by junction temperature $T_{J(MAX)}$ =150 $^{\circ}$ C.
- D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

- G. The maximum current rating is package limited.
- H. These tests are performed with the device mounted on 1 in FR-4 board with 2oz. Copper, in a still air environment with TA=25° C.

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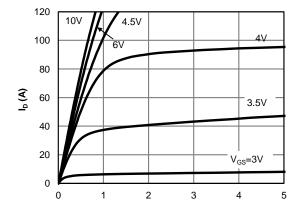
B. The power dissipation P_D is based on $T_{J(MAX)}$ =150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

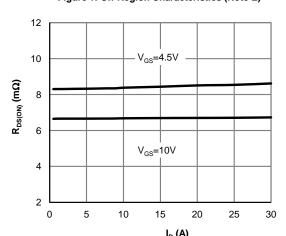
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsirk, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.



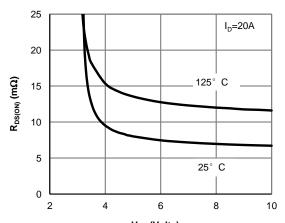
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



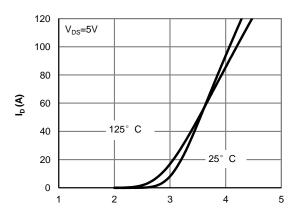
 V_{DS} (Volts) Figure 1: On-Region Characteristics (Note E)



 ${
m I_D}\left({
m A}\right)$ Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



V_{GS} (Volts) Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



V_{GS} (Volts) Figure 2: Transfer Characteristics (Note E)

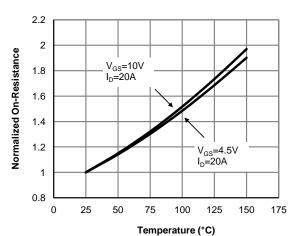
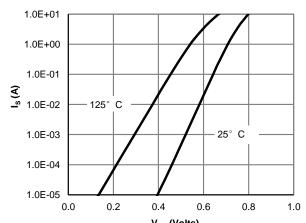


Figure 4: On-Resistance vs. Junction Temperature (Note E)



V_{SD} (Volts) Figure 6: Body-Diode Characteristics (Note E)

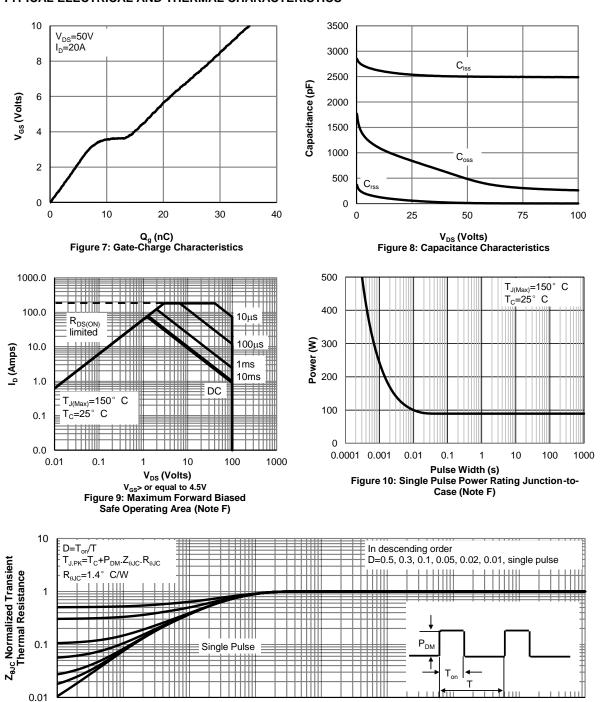
1000

10

100



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

0.1

0.01

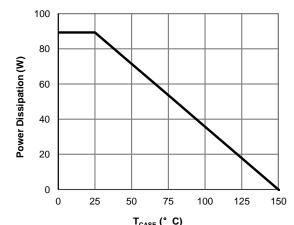
0.001

1E-05

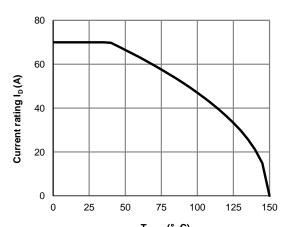
0.0001



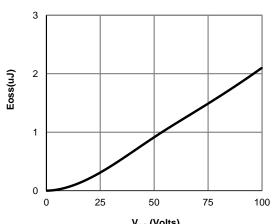
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



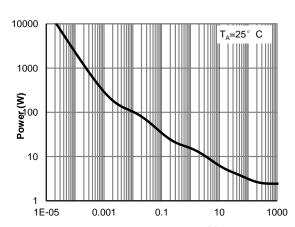
 T_{CASE} (° C) Figure 12: Power De-rating (Note F)



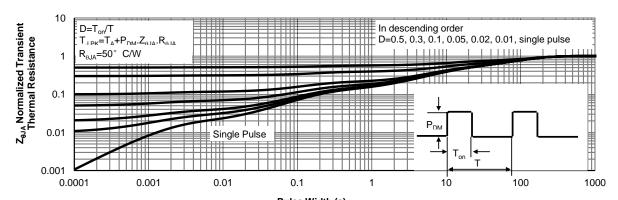
 T_{CASE} (° C) Figure 13: Current De-rating (Note F)



V_{DS} (Volts) Figure 14: Coss stored Energy



Pulse Width (s)
Figure 15: Single Pulse Power Rating Junctionto-Ambient (Note H)



Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

Figure A: Gate Charge Test Circuit & Waveforms

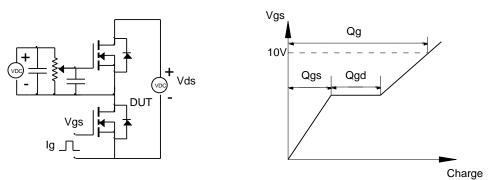


Figure B: Resistive Switching Test Circuit & Waveforms

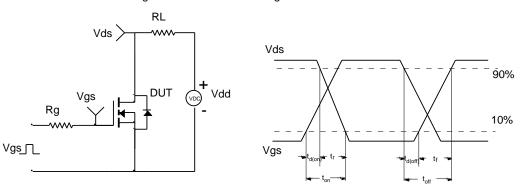


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

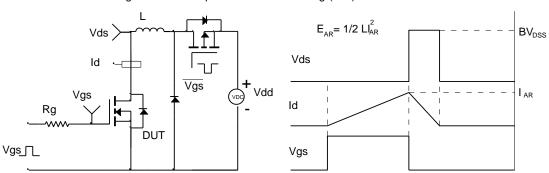


Figure D: Diode Recovery Test Circuit & Waveforms

